

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/557,577 KAYYEM ET AL.	
		Examiner	Art Unit Ardin Marschel	Page 1 of 1

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	C	US-			
	D	US-			
	E	US-			
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	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

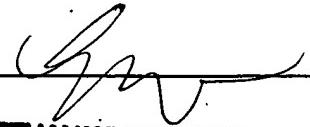
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ETHAN WHISENANT
PRIMARY EXAMINER

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